

Notice of References Cited	Application/Control No. 10/540,527		Applicant(s)/Patent Under Reexamination INOUE ET AL.	
	Examiner John P. Sheehan		Art Unit 1793	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,132,019	11-2006	Koshiba et al.	148/304
*	B	US-6,594,157	07-2003	Yoshida et al.	363/14
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
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	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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